

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/566,714 ISHIBASHI ET AL.	
		Examiner	Art Unit SOPHIE HON	1794 Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Theodore Oakberg, Birefringence Measurement, PEMlabs, Hinds Instruments, 2005.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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